

IEUVI Optics TWG Meeting March 2, 2005 San Jose, California

5:00	On site registration	
10 min	Buffet Dinner is Served	
10 min	Introduction: Review of Areas of Possible Cooperation and Discussion of Desired Meeting Output	Ginger Edwards
10 min	EUV Optics Contamination and Lifetime: IBM Perspective & Expectations	Gregg Gallatin
10 min	EUV Optics Contamination and Lifetime: Intel Perspective & Expectations	Manish Chandhok
10 min	Origins of Contamination from EUV Sources	Dick Anderson, Sandia
10 min	Resist Outgassing Summary	Kim Dean, SEMATECH
10 min	Hydrocarbon Contamination Monitoring Update	Anthony Kean, BOC Edwards
10 min	Intel Resist Outgassing Metrology and Specs	Heidi Cao, Intel
10 min	Optics Lifetime Testing Update	Tom Lucatorto, NIST
10 min	Update on Ru Oxidation Modeling	Yoshio Gomei, Canon

(6:40 pm)

(Continued....)

IEUVI Optics TWG Meeting March 2, 2005 (continued)

10 min	E-beam Based Lifetime Testing Update	Dick Anderson, Sandia
10 min	Update from ASET	Iwao Nisiyama, ASET
10 min	Update from EUVA	Yasuaki Fukuda and Takashi Aoki, EUVA
10 min	Update from PTB	Christian Laubis, PTB
10 min	Update from TNO TPD	Bas Mertens, TNO TPD
10 min	Update from CEA-LETI	Cyril Vanneuffl, CEA-LETI
10 min	Update from Lawrence Livermore National Laboratory	John Taylor, LLNL
10 min	Discussion	
30 min	Group 1 Compiles Cooperation Topics; Group 2 Summarizes Key Results from Updates	All
10 min	Present Compilation of Key Results	Leader of Group 1
10 min	Present Compilation of Cooperation Topics	Leader of Group 2
10 min	Wrap-Up and Plans for Next Meeting	Ginger Edwards, SEMATECH
9:00	Adjourn	